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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPLICATION NO.		CLASS		SUBCLASS		GAU		EXAMINER	
APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU					
10000089	12/04/2001	714 324	2122	2133 3050					
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<b>**CONTINUING DATA VERIFIED:</b>									
<b>** FOREIGN APPLICATIONS VERIFIED:</b> JAPAN 2000-372231 12/07/2000 JAPAN 2001-205179 07/05/2001									
PG-PUB		DO NOT PUBLISH <input type="checkbox"/>			RESCIND <input type="checkbox"/>				
Foreign priority claimed		<input type="checkbox"/> yes <input type="checkbox"/> no			ATTORNEY DOCKET NO				
35 USC 119 conditions met		<input type="checkbox"/> yes <input type="checkbox"/> no			1075.1385				
Verified and Acknowledged Examiners's initials									
TITLE : Testing apparatus and testing method for an integrated circuit, and integrated circuit									
U.S. DEPT. OF COMMERCE/PAT. & TRADEMARK OFFICE (Rev. 12-94)									

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<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
		Total Claims	
		Print Claim for O.G.	
<b>ISSUE FEE</b>		<b>DRAWING</b>	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.
		Print Fig.	
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		Application Examiner	
		<b>PREPARED FOR ISSUE</b>	
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